

**Search Notes**

Application/Control No.

10/757,237

Examiner

Vincent Lai

Applicant(s)/Patent under  
Reexamination

DEWITT ET AL.

Art Unit

2181

**SEARCHED**

Class	Subclass	Date	Examiner
712	240	4/3/2006	VL
712	239	4/3/2006	VL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search terms: counter, statistic, cache, mode, branch count, branch statistics, conditional, store, times, program	4/3/2006	VL